

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 03500.015729.		APPLICATION NO. 09/940,643	
			APPLICANT Shin Kitamura et al.			
			FILING DATE August 29, 2001		GROUP 2831	

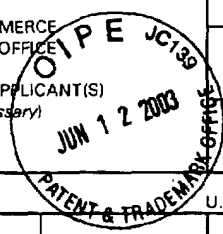
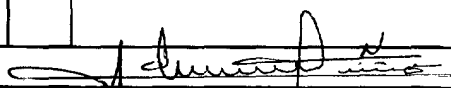
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FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
AN ✓	05-211029	08/20/93	Japan	H01J	1/30	Abst.
AN ✓	10-199398	07/31/98	Japan	H01J	1/30	Abst.
AN ✓	1999-019614	03/15/99	Korea	H01J	17/49	Abst.

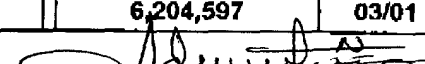
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	

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				APPLICANT SHIN KITAMURA ET AL.			
				FILING DATE August 29, 2001		GROUP 2879	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
AN		0 836 217 A1	4/1998	EPO	H01J	29/94	
AN		99/58748	11/1999	WO	D01F	9/127	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED 12/11/03			

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U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AN	5,982,091	11/99	Konishi	313	495	
	6,400,091 B1	06/02	Deguchi et al.	315	169.1	
	6,472,814 B1	10/02	Yamanobe et al.	313	495	11/13/98
	5,872,422	02/99	Xu et al.	313	311	
	6,087,765	07/00	Coll et al.	313	309	
	2002/0009637A1	01/02	Murakami et al.	429	213	02/05/01
	5,847,495	12/98	Yamanobe et al.	313	310	
	5,066,883	11/91	Yoshioka et al.	313	309	
	6,455,021 B1	09/02	Saito	423	447.3	07/20/99
	6,471,936 B1	10/02	Chen et al.	423	658.2	03/02/00
	4,728,851	03/88	Lambe	313	309	
	5,773,921	06/30/98	Keesman et al.	313	309	
	5,973,444	10/26/99	Xu et al.	313	309	
	5,935,639	8/10/99	Sullivan et al.	427	78	
	4,956,578	9/11/90	Shimizu et al.	315	3	
	5,185,554	2/9/93	Nomura et al.	313	495	
	6,448,709	9/02	Chuang et al.	313	497	
AN	6,204,597	03/01	Xie et al.	313	310	
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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AN	5,577,943	11/96	Vickers et al.	445	24	
	2002/136896	09/26/00	Takikawa et al.	428	408	
	5,192,240	03/09/93	Komatsu	445	24	
	5,214,346	05/25/93	Komatsu	313	309	
	5,382,867	01/17/95	Maruo et al.	313	309	
	5,612,587	03/18/97	Itoh et al.	313	309	
	6,313,572 B1	11/06/01	Yamada	313	310	
	6,135,839	10/24/00	Iwase et al.	445	24	
	2001/0006232	07/05/01	Choi et al.	257	10	
	4,816,289	03/89	Komatsu et al.	423	447.3	
	5,443,859	08/95	Nagata	427	122	
	5,618,875	04/97	Baker et al.	524	495	
	5,690,997	11/97	Grow	427	249.1	
	6,129,602	10/00	Yamanobe	445	24	
	6,228,904	05/01	Yadav et al.	523	210	
	6,333,016	12/01	Resasco et al.	423	447.3	
	6,413,487	07/02	Resasco et al.	423	447.3	
AN	6,445,006	09/02	Brandes et al.	257	76	
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U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AN	5,981,305	11/99	Hattori	438	20	
	6,290,564	9/01	Talin et al.	445	50	
	5,458,784	10/95	Baker et al.	210	674	
	6,331,690 B1	12/01	Yudasaka et al.	219	121.6	
	5,965,267	10/99	Nolan et al.	428	408	
	6,309,612 B1	05/02	Kotaki et al.	347	85	
	5,872,541	02/99	Yoshioka et al.	345	74.1	
	5,543,684	08/96	Kumar et al.	313	495	
	5,551,903	9/96	Kumar et al.	445	24	
	4,900,483	2/90	Witzke et al.	313	309	
	5,500,200	3/96	Mandeville et al.	423	447.3	
	5,726,524	3/98	Debe	313	309	
	2002/0047562 A1	04/25/02	Kitamura et al.	315	169.3	
	5,770,918	06/98	Kawate et al.	313	495	
	5,185,554	02/93	Nomura et al.	313	495	
	2002/0146958 A1	10/02	Ono et al.	445	24	
AN	2003/0048056 A1	03/03	Kitamura et al.	313	311	
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APPLICANT Shin Kitamura et al.		FILING DATE August 29, 2001		GROUP 2879	

FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
AN ✓	11-194134	07/99	Japan	G01N	37/00	Abst., European Equivalent: 0 893 508 A2 & Counterpart U.S. Patent 6,513,572
AN ✓	11-139815	05/99	Japan	C01B	31/02	Abst.
AN ✓	0 535 953 B1	01/96	EPO	H01J	1/30	English
✓	0 290 026 B1	02/93	EPO	H01J	3/02	English
✓	1 122 344 A2	08/01	EPO	D01F	9/127	English
✓	WO 01/93292 A1	12/01	PCT	H01J	1/304	English
✓	WO 89/07163	08/10/89	Japan	D01F	9/12	English
✓	WO 90/07023	06/28/90	PCT	D01F	9/12	English
✓	08-115652	05/07/96	Japan	H01J	1/30	Abst. & Trans.
✓	0 758 028 A2	02/12/97	EPO	D01F	9/127	English
✓	WO 98/05920	02/12/98	PCT	G01B	7/34	English
✓	0 394 698 A2	10/31/90	EPO	H01J	1/30	English
✓	2000/277003	10/06/00	Japan	H01J	9/02	Counterpart U.S. Patent 2002/136886
✓	0 797 233 A2	09/24/97	EPO	H01J	1/30	English
✓	0 980 089 A1	02/16/00	EPO	H01J	1/30	English
✓	0 986 084 A2	03/15/00	EPO	H01J	1/30	English
✓	1 117 118 A1	07/18/01	EPO	H01J	1/312	English
AN ✓	0 716 439 A1	06/12/96	EPO	H01J	3/02	English

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
AN ✓	2-112125	04/24/90	JAPAN	H01J	1/30	Abst. & Counterpart U.S. Patent 4,958,578
✓	3-20941	01/29/91	JAPAN	H01J	31/12	Abst. & Counterpart U.S. Patent 5,185,554
✓	5-211029	08/20/93	JAPAN	H01J	1/30	No
✓	8-264109	10/11/96	JAPAN	H01J	1/30	Abst.
✓	9-82214	3/28/97	JAPAN	H01J	1/30	Abst. & European Equivalent 0 718 439
✓	1 113 478 A1	07/01	EPO	H01J	3/02	English
✓	0 913 508 A2	05/06/99	EPO	D01F	9/127	English
✓	09-188600	07/22/97	Japan	C30B	29/62	Abst.
✓	A1 443 865	08/28/91	EPO	H01J	21/10	English
✓	04-212236	03/08/92	Japan	H01J	1/30	Counterpart U.S. Patents 5,182,240, 5,214,348 & EP 0 443 865
✓	03-295131	12/26/91	Japan	H01J	1/30	Counterpart U.S. Patents 5,182,240, 5,214,348 & EP 0 443 865
✓	05-159696	06/25/93	Japan	H01J	1/30	Counterpart U.S. Patents 5,382,897 & EP 0 535 853
✓	05-198253	08/06/93	Japan	H01J	1/30	Counterpart U.S. Patents 5,382,897 & EP 0 535 853
AN ✓	05-274997	10/22/93	Japan	H01J	1/30	Abst. & Counterpart U.S. Patent 5,612,587
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<i>AN</i>	✓	11-232997	08/27/99	Japan	H01J	1/30	Counterpart U.S. Patent 6,313,572 & EP 0 936 850
	✓	0 936 650 A1	08/18/99	EPO	H01J	3/02	English
	✓	10-289650	10/27/98	Japan	H01J	1/30	Counterpart U.S. Patent 6,138,534 & EP 0 871 198
	✓	0 871 195 A1	10/14/98	EPO	H01J	1/30	English
	✓	0 290 026 A1	11/88	EPO	H01J	3/02	English
	✓	0 535 953 A2	4/93	EPO	H01J	1/30	English
	✓	0 836 217 A1	04/98	EPO	H01J	29/94	English
	✓	WO 99/58748	11/99	PCT	D01F	9/127	English
	✓	CN 1181607A	5/98	China			English Counterparts 0 836 217 & 98/58748
	✓	1 187 161 A2	03/13/02	EPO	H01J	3/02	English
	✓	1 102 299 A1	5/01	EPO	H01J	1/30	English
	✓	1 096 533 A1	5/01	EPO	H01J	9/02	English
	✓	WO 01/26130	4/01	WIPO	H01J	9/20	English
	✓	GB 2 308 495	6/97	UK	H01J	1/20	English
	✓	1 120 877 A1	8/01	EPO	H02G	5/06	English
<i>AR</i>	✓	1-309242	12/89	Japan	H01J	37/06	Abst.
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AN ✓	11-162334	6/99	JAPAN	H01J	9/02	Abst.
✓	2000-57934	2/00	JAPAN	H01J	1/304	Abst.
✓	2000-86216	3/00	JAPAN	C01B	31/02	Abst.
✓	2000-90809	3/00	JAPAN	H01J	1/304	Abst.
✓	2001-288625 A	10/01	Japan	D01F	9/127	Abst., Counterpart U.S. Patent 2002/00009637 & EP 1 122 344
✓	0 433 507 A1	6/91	EPO	D01F	9/127	English
✓	03-260119	11/91	Japan	D01F	9/127	Abst. & Counterpart U.S. Patent 4,900,483
✓	2001-52598	2/01	Japan	H01J	1/316	Abst.
✓	2000-95509	4/00	Japan	C01B	31/02	Abst.
✓	0 451 208 B1	3/00	EPO	D01F	9/12	English
✓	2000-208028	7/00	Japan	H01J	1/304	Abst.
✓	0 936 650 A1	8/99	EPO	H01J	3/02	English
✓	08-298068	11/96	Japan	H01J	1/30	Abst.
✓	2001-162600	06/19/01	Japan	B82B	1/00	Abst.
✓	0 758 028 B1	09/11/02	EPO	D01F	9/127	English
✓	0 913 508 A3	5/99	EPO	D01F	9/127	English
AN ✓	10-149760	06/02/98	Japan	H01J	1/30	Abst.
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AN	✓	R.T.K. Baker et al., "Formation of Carbonaceous Deposits from the Platinum-Iron Catalyzed Decomposition of Acetylene," 37 J. Catal. 101-105 (1975).	
	✓	R.T.K. Baker, "Catalytic Growth of Carbon Filaments," 27 (3) Carbon 315-323 (1989).	
	✓	S. Iijima, "Helical Microtubules of Graphitic Carbon," Nature, Vol. 345, 56-58 (1991).	
	✓	T. W. Ebbesen et al., "Large-Scale Synthesis of Carbon Nanotubes," Nature, Vol. 358, 220-222 (1992).	
	✓	W. A. DeHeer et al., "Aligned Carbon Nanotube Films: Production and Optical and Electronic Properties," Science Vol. 268, 845-847 (1995).	
	✓	T. Guo et al., "Catalytic Growth of Single-Walled Nanotubes by Laser Vaporization," Chem Phys. Lett., Vol. 243, 49-54 (1995).	
	✓	A. G. Rinzler et al., "Unraveling Nanotubes: Field Emission from an Atomic Wire," Science, Vol. 269, 1550-1553 (1995).	
	✓	W. A. DeHeer et al., "A Carbon Nanotube Field-Emission Electron Source," Science, Vol. 270, 1179-1180 (1995).	
	✓	T. Kyotani et al., "Preparation of Ultrafine Carbon Tubes in Nanochannels of an Anodic Aluminum Oxide Film," Chem. Mater., Vol. 8, 2109-2113 (1996).	
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	✓	H. Dai et al., "Nanotubes as Nanoprobes in Scanning Probe Microscopy," Nature, Vol. 384, 147-150 (1996).	
	✓	A. C. Dillon et al., "Storage of Hydrogen in Single-Walled Carbon Nanotubes," Nature, Vol. 386, 377-379 (1997).	
AN	✓	W.P. Dyke et al., "Field Emission", <i>Advances in Electronics and Electron Physics</i> , Vol. 8, (1956) pp. 89-185	
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AN	✓	C.A. Mead, "Operation of Tunnel-Emission Devices", <i>Journal of Applied Physics</i> , Vol. 32, No. 4, (1961), pp. 646-652	
	✓	Toshiaki Kusunoki et al., "Fluctuation-Free Electron Emission from Non-Formed Metal-Insulator-Metal (MIM) Cathodes Fabricated by Low Current Anodic Oxidation", <i>Japanese Journal of Applied Physics</i> , Vol. 32 No. 11B, (1993), p. L1695-1697	
	✓	M.I. Elinson et al., "The Emission of Hot Electrons and the Field Emission of Electrons from Tin Oxide", <i>Radio Engineering and Electronic Physics</i> , (1965) pp. 1290-1296	
	✓	G. Dittmer, "Electrical Conduction and Electron Emission of Discontinuous Thin Films", <i>Thin Solid Films</i> , Vol. 9, (1972) pp. 317-329	
	✓	M. Hartwell et al., "Strong Electron Emission from Patterned Tin-Indium Oxide Thin Film", <i>IEEE Trans. Ed. Conf.</i> , (1983) pp.519-521	
	✓	Hisashi Araki et al., "Electroforming and Electron Emission of Carbon Thin Films, <i>Journal of the Vacuum Society of Japan</i> , 1983 (with English Abstract on p. 22)	
	✓	Rodriguez et al., "Catalytic Engineering of Carbon Nanostructures," <i>Langmuir</i> 11, 3862-3866 (1995).	
	✓	W. Zhu Et Al., <i>Electron Field Emission From Nanostructured Diamond and Carbon Nanotubes</i> , <i>Solid State Electronics</i> , Vol. 45, 2001, pp. 921-928	
	✓	J.M. Bonard Et Al., <i>Field Emission From Carbon Nanotubes: The First Five Years</i> , <i>Solid State Electronics</i> , Vol. 45, 2001, pp. 893-914	
	✓	A.M. Rao et al., "In Situ-grown Carbon Nanotube Array of with Excellent Field Emission Characteristics," <i>Applied Physics Letter</i> , Vol. 76, No. 25, pp. 3813-3815 (2000).	
	✓	Cheol Jin Lee et al., "Carbon Nanofibers Grown on Sodalime Glass at 500 °C Using Thermal Chemical Vapor Deposition," <i>Chemical Physics Letters</i> 340, pp. 413-418 (2001).	
	✓	Sashiro Uemura et al., "Carbon Nanotube FED with Graphite-Nano-Fiber Emitters," <i>ISSN 1083-1312</i> , pp. 398-401.	
AN	✓	Q. H. Wang et al., "A Nanotube-Based Field-Emission Flat Panel Display," <i>Applied Physics Letters</i> , Vol. 72, No. 22, June 1998, pp. 2912-2913	
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